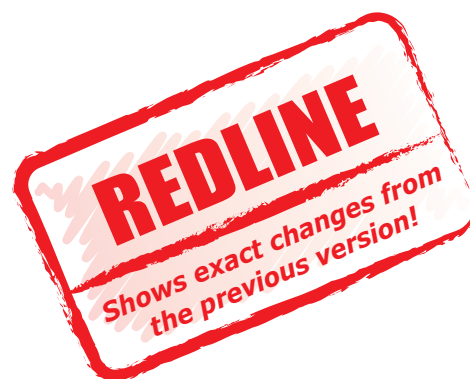




IEEE Standard for Exposed Semiconducting Shields on High-Voltage Cable Joints and Separable Connectors

IEEE Power Engineering Society

Sponsored by the
Insulated Conductors Committee



IEEE
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Abstract: Design test for shield resistance and a simulated fault-current initiation for exposed semiconducting shields used on cable accessories, specifically joints and separable insulated connectors rated 15 kV through 35 kV are provided in this standard.

Keywords: fault-current initiation, shield resistance

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